International **ICR** Rectifier

AUTOMOTIVE MOSFET

Features

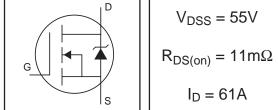
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Timax
- Lead-Free

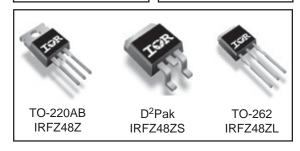
Description

Specifically designed for Automotive applications, this HEXFET[®] Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of

other applications. Absolute Maximum Ratings







	Parameter	Max.	Units	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	61	A	
$I_{\rm D} @ T_{\rm C} = 100^{\circ}{\rm C}$	Continuous Drain Current, V _{GS} @ 10V (See Fig. 9)	43		
I _{DM}	Pulsed Drain Current ①	240		
$P_{D} @T_{C} = 25^{\circ}C$	Maximum Power Dissipation	91	W	
	Linear Derating Factor	0.61	W/°C	
V _{GS}	Gate-to-Source Voltage	± 20	V	
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) 2	73	mJ	
E _{AS} (tested)	Single Pulse Avalanche Energy Tested Value Ø	120	1	
I _{AR}	Avalanche Current ①	See Fig.12a,12b,15,16	A	
E _{AR}	Repetitive Avalanche Energy ®		mJ	
TJ	Operating Junction and	-55 to + 175	°C	
T _{STG}	Storage Temperature Range			
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)]	
	Mounting torque, 6-32 or M3 screw	10 lbf∙in (1.1N•m)		

	Parameter	Тур.	Max.	Units
$R_{ ext{ heta}JC}$	Junction-to-Case		1.64	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		
$R_{\theta JA}$	Junction-to-Ambient		62	Ī
R_{\thetaJA}	Junction-to-Ambient (PCB Mount, steady state)®		40	

HEXFET[®] is a registered trademark of International Rectifier.

IRFZ48Z/S/LPbF

Static @ T_J = 25°C (unless otherwise specified)

International **ISR** Rectifier

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.054		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		8.6	11	mΩ	V _{GS} = 10V, I _D = 37A ④
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$
gfs	Forward Transconductance	24			S	V _{DS} = 25V, I _D = 37A
I _{DSS}	Drain-to-Source Leakage Current			20	μA	$V_{DS} = 55V, V_{GS} = 0V$
				250		$V_{DS} = 55V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			200	nA	V _{GS} = 20V
	Gate-to-Source Reverse Leakage			-200		V _{GS} = -20V
Q _g	Total Gate Charge		43	64	nC	I _D = 37A
Q _{gs}	Gate-to-Source Charge		11	16		$V_{DS} = 44V$
Q _{gd}	Gate-to-Drain ("Miller") Charge		16	24		V _{GS} = 10V ④
t _{d(on)}	Turn-On Delay Time		15		ns	$V_{DD} = 28V$
t _r	Rise Time		69			I _D = 37A
t _{d(off)}	Turn-Off Delay Time		35			$R_{G} = 12\Omega$
t _f	Fall Time		39			V _{GS} = 10V ④
L _D	Internal Drain Inductance		4.5		nH	Between lead, p
						6mm (0.25in.)
L _S	Internal Source Inductance		7.5			from package 🔍 🕂
						and center of die contact
C _{iss}	Input Capacitance		1720		pF	$V_{GS} = 0V$
C _{oss}	Output Capacitance		300			$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		160			f = 1.0MHz, See Fig. 5
C _{oss}	Output Capacitance		1020			$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$
C _{oss}	Output Capacitance		230		1	$V_{GS} = 0V, V_{DS} = 44V, f = 1.0MHz$
C _{oss} eff.	Effective Output Capacitance		380		1	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 44V$

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current			61		MOSFET symbol
	(Body Diode)				А	showing the
I _{SM}	Pulsed Source Current		-	240		integral reverse
	(Body Diode) ①					p-n junction diode.
V _{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 37A, V_{GS} = 0V @$
t _{rr}	Reverse Recovery Time		20	31	ns	$T_J = 25^{\circ}C, I_F = 37A, V_{DD} = 30V$
Q _{rr}	Reverse Recovery Charge		13	20	nC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

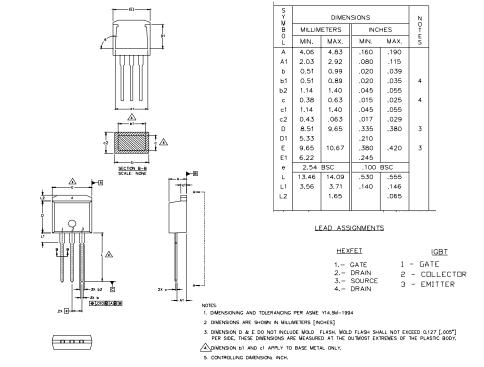
- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by T_{Jmax}, starting T_J = 25°C, L =0.11mH, R_G = 25Ω, I_{AS} = 37A, V_{GS} =10V. Part not recommended for use above this value.
- 3 I_{SD} \leq 37A, di/dt \leq 920A/µs, V_{DD} \leq V_{(BR)DSS}, T_J \leq 175°C.
- ④ Pulse width \leq 1.0ms; duty cycle \leq 2%.
- \tilde{S} Coss eff. is a fixed capacitance that gives the same charging time as Coss while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑤ Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑦ This value determined from sample failure population. 100% tested to this value in production.
- Inis is applied to D²Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

IRFZ48Z/S/LPbF

International

TO-262 Package Outline

Dimensions are shown in millimeters (inches)



TO-262 Part Marking Information

